TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π -MOSIV)

2SK4013

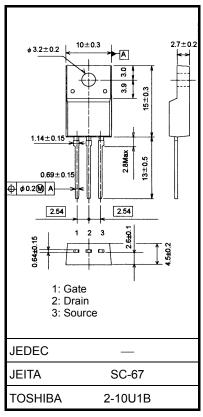
Switching Regulator Applications

Unit: mm

- Low drain-source ON resistance: RDS (ON) = 1.35Ω (typ.)
- High forward transfer admittance: $|Y_{fs}| = 5.0 \text{ S (typ.)}$
- Low leakage current: $I_{DSS} = 100 \mu A \text{ (max) (V}_{DS} = 640 \text{ V)}$
- Enhancement-model: $V_{th} = 2.0 \sim 4.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$

Absolute Maximum Ratings (Ta = 25°C)

Characte	eristics	Symbol	Rating	Unit	
Drain-source voltage	•	V_{DSS}	800	V	
Drain-gate voltage (F	$R_{GS} = 20 \text{ k}\Omega$)	V_{DGR}	800	V	
Gate-source voltage		V _{GSS}	±30	V	
Drain current	DC (Note 1)	I _D	6	Α	
	Pulse (Note 1)	I _{DP}	18	^	
Drain power dissipat	ion (Tc = 25°C)	P_{D}	45	W	
Single pulse avalance	he energy (Note 2)	E _{AR}	317	mJ	
Avalanche current		I _{AR}	6	Α	
Repetitive avalanche	e energy (Note 3)	E _{AR}	4.5	mJ	
Channel temperature	e	T _{ch}	150	°C	
Storage temperature	range	T _{stg}	-55~150	°C	

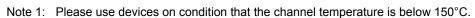


Weight: 1.7 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

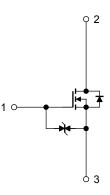
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	2.78	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	62.5	°C/W



Note 2: $V_{DD}=90~V,~T_{ch}=25^{\circ}C$ (initial), $L=14.5~mH,~R_{G}=25~\Omega,~I_{AR}=6~A$

Note 3: Repetitive rating; pulse width limited by maximum channel temperature.

This transistor is an electrostatic sensitive device. Please handle with caution.





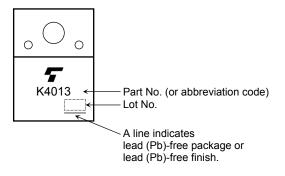
Electrical Characteristics (Ta = 25°C)

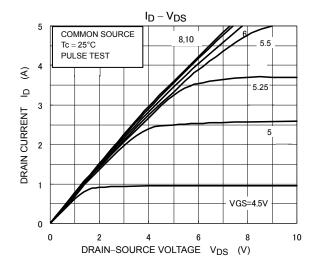
Chara	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I _{GSS}	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$		_	±10	μА
Drain-source brea	akdown voltage	V (BR) GSS	$I_G = \pm 10 \ \mu A, \ V_{DS} = 0 \ V$	±30	_	_	V
Drain cut-OFF cu	rrent	I _{DSS}	V _{DS} = 640 V, V _{GS} = 0 V	_	_	100	μА
Drain-source brea	akdown voltage	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	800	_	_	V
Gate threshold voltage		V _{th}	V _{DS} = 10 V, I _D = 1 mA	2.0	_	4.0	V
Drain-source ON resistance		R _{DS} (ON)	V _{GS} = 10 V, I _D = 3 A	_	1.35	1.7	Ω
Forward transfer	orward transfer admittance $ Y_{fS} $ $V_{DS} = 20 \text{ V}, I_D = 3 \text{ A}$		2.5	5.0	_	S	
Input capacitance		C _{iss}		_	1400	_	pF
Reverse transfer capacitance		C _{rss}	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	30	_	
Output capacitance		Coss		_	130	_	
Switching time	Rise time	t _r	$V_{GS}^{10 \text{ V}} V_{GS}^{10 \text{ V}} V_{DD}^{10 \text{ A}} = 133 \Omega$ $V_{DD}^{10 \text{ V}} V_{DD}^{10 \text{ A}} = 10 \mu \text{s}$ $V_{DD}^{10 \text{ V}} V_{DD}^{10 \text{ A}} = 10 \mu \text{s}$	_	25	_	- ns
	Turn-ON time	t _{on}		_	80	_	
	Fall time	t _f		_	65	_	
	Turn-OFF time	t _{off}		_	220	_	
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 6 \text{ A}$	_	45	_	nC
Gate-source charge		Q _{gs}		_	25	_	
Gate-drain ("miller") charge		Q _{gd}		_	20	_	

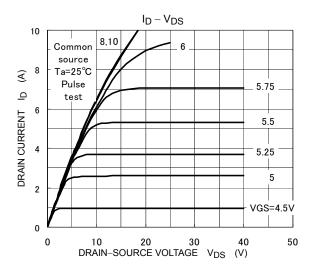
Source-Drain Ratings and Characteristics (Ta = 25°C)

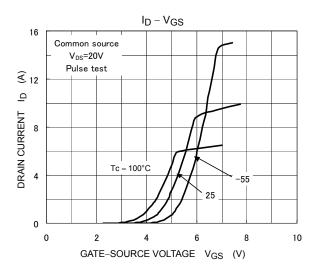
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I_{DR}	_	_	_	6	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	18	Α
Forward voltage (diode)	V_{DSF}	I _{DR} = 6 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	$I_{DR} = 6 \text{ A}, V_{GS} = 0 \text{ V},$	_	1100	_	ns
Reverse recovery charge	Qrr	dI _{DR} /dt = 100 A/μs	_	10	_	μС

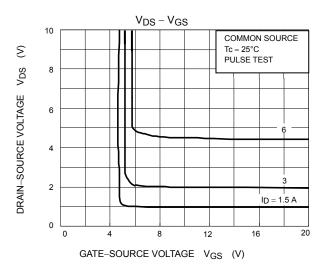
Marking

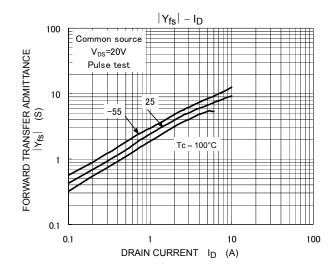


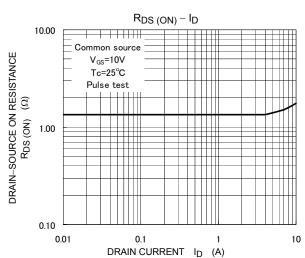


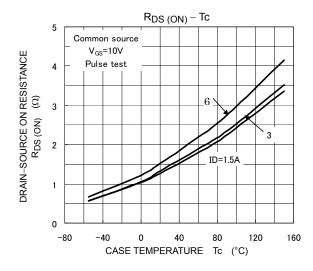


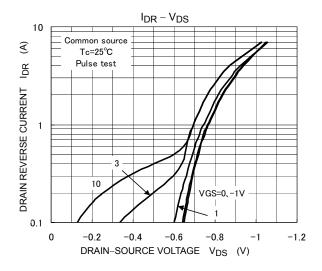


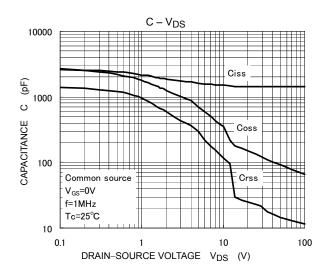


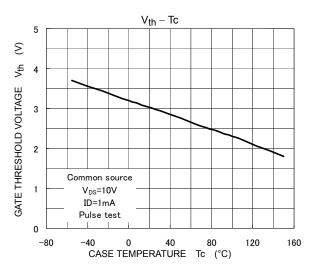


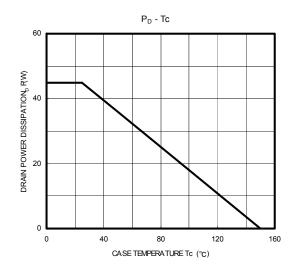


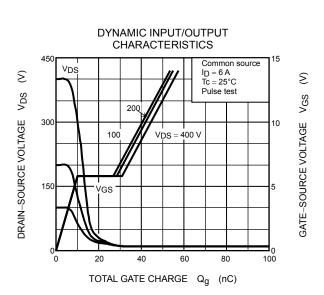


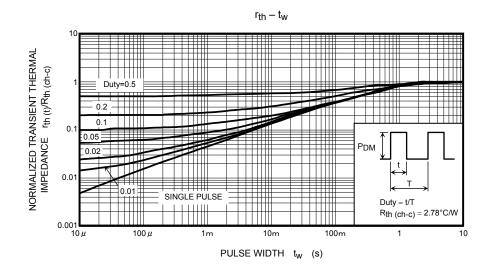


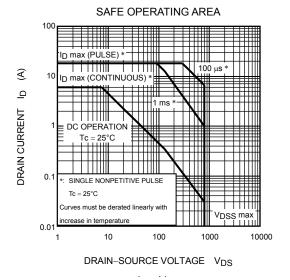


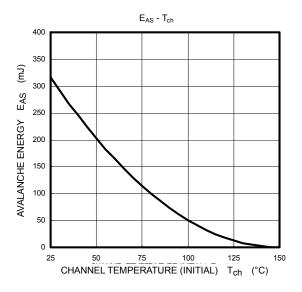


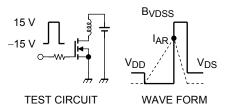












$$R_G = 25 \Omega$$

 $V_{DD} = 90 \text{ V, L} = 14.5 \text{ mH}$ $E_{AS} = \frac{1}{2} \cdot L \cdot l^2 \cdot \left(\frac{BVDSS}{BVDSS - VDD} \right)$

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20070701-EN

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